## Application/Control No. Applicant(s)/Patent Under Reexamination NAH ET AL. Examiner Dennis-Doon Chow Applicant(s)/Patent Under Reexamination NAH ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

				C.C. I ATENT DOCUMENTO	
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,590,553	07-2003	Kimura et al.	345/92
	В	US-			
-	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	м	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N						
	0		_		·		
	Р						
	Q						
	R						
	s						
	Т						

## **NON-PATENT DOCUMENTS**

100.1.1.2.1.2.2.2.2.2.2.2.2.2.2.2.2.2.2.								
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	V							
	w							
	x							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.